

CoolGaN[™] Transistor 80 V G3

Features

- Enhancement mode power transistor normally OFF switch
- No reverse recovery chargeReverse conduction capability

- Low gate charge, low output charge
 Qualified according to JEDEC for target applications

Potential applications

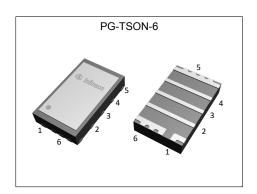
- Telecom AC/DC
- Telecom DC/DC
- · Charger/Adapter
- Battery powered tools
- · e-Mobility, UAVs
- Robotics

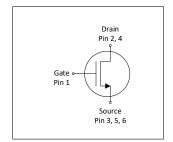
Product validation

Fully qualified according to JEDEC for Industrial Applications



Parameter	Value	Unit
V _{DS}	80	V
$R_{\mathrm{DS(on),max}}$	2.5	$m\Omega$
I _D	85	A
Qoss	35	nC
Q _G	11	nC
Qrr	0	nC









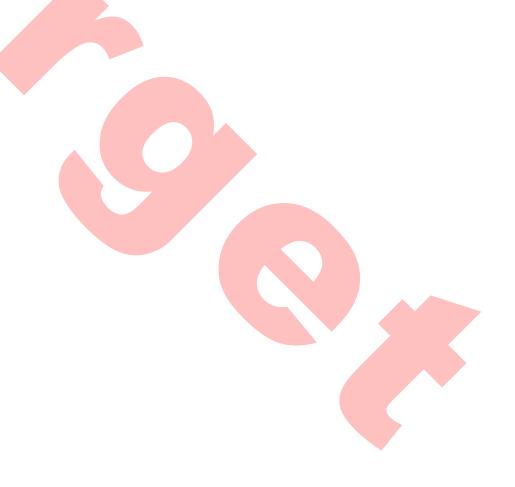
Type / Ordering Code	Package	Marking	Related Links
IGC025S08S1	PG-TSON-6	25SD1	-

CoolGaN[™] Transistor 80 V G3 IGC025S08S1



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1 Maximum ratings

Table 2 Maximum ratings

Dawwater	Oh a l	Values			1114		
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous drain-source voltage	V _{DS}	-	-	80	V	V _{GS} =0 V	
Pulsed drain-source voltage ¹⁾	V _{DS, pulse}	-	-	96	V	V _{GS} =0 V, 1 h total time	
Continuous drain current	ID	-	-	85 23	А	V _{GS} =5 V, T _C =25 °C V _{GS} =5 V, T _A =25 °C, R _{THJA} =38 °C/W ²⁾	
Pulsed drain current ³⁾	$I_{ m D,pulse}$	-	-	t.b.d. t.b.d.	А	Tj=25 °C Tj=150 °C	
Gate-source voltage	V _{GS}	-4 -6.5	5 -	5.5 6.5	V	Continuous Pulsed	
Power dissipation	P _{tot}	-	-	45 3.3	W	T _C =25 °C T _A =25 °C, R _{THJA} =38 °C/W	
Storage temperature	T _{stg}	-55	-	150	°C	-	
Operating temperature	T _j	-40	-	150	°C	-	

2 Thermal characteristics

Table 3 Thermal characteristics

Dovernator	Complete	Values			11:4	Note / Total Constitute		
Parameter	Symbol	Min.	Тур.	Ma <mark>x.</mark>	Unit	Note / Test Condition		
Thermal resistance, junction - case, top	$R_{thJC(top)}$	-	0.5	0.6	°C/W	-		
Thermal resistance, junction - case, bottom	R _{thJC(bottom)}	-	1.9	2.8	°C/W	-		
Device on 1 layer PCB	R _{thJA}	-	60	70	°C/W	1s0p		
Device on 4 layer PCB	R _{thJA}	-	38	-	°C/W	2s2p with vias		

¹⁾ Provided as measure of robustness under abnormal operating conditions and not recommended for normal operation

 $^{^{\}rm 2)}$ Device on 4-layer FR4 PCB, vertical in still air.

³⁾ Pulse current limited by transfer characteristic. See diagram 6. Target Data Sheet

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Electrical characteristics

at T_j =25 °C, unless otherwise specified

Table 4 Static characteristics

Develope	Cumbal	Values			11	Nata / Tank Oam distant	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Gate threshold voltage ¹⁾	V _{GS(th)}	1.2	2.0	2.9	V	$V_{\rm DS}$ = $V_{\rm GS}$, $I_{\rm D}$ =10 mA, measured within 10 ms after a pre-bias at $V_{\rm GS}$ =5 V, $V_{\rm DS}$ =0 V for at least 5 ms	
Drain-source leakage current	I _{DSS}	-	0.2 20	-	μΑ	V _{DS} =80 V, V _{GS} =0 V, T _j =25 °C V _{DS} =80 V, V _{GS} =0 V, T _j =125 °C	
Gate-source leakage current	less	- - -	23 0.01 130 15	- - -	μΑ	V _{GS} =5 V, T _j =25 °C V _{GS} =-4 V, T _j =25 °C V _{GS} =5 V, T _j =125 °C V _{GS} =-4 V, T _j =125 °C	
Drain-source on-state resistance ²⁾	R _{DS(on)}	-	1.9	2.5	mΩ	V _{GS} =5 V, I _D =25 A	
Gate resistance ³⁾	R _G	_	0.5	-	Ω	-	

Dynamic characteristics³⁾ Table 5

Dovomotor	Cymbal	Values		Unit	Note / Test Condition		
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Input capacitance	Ciss	-	1000	-	pF	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz	
Output capacitance	Coss	-	510	-	pF	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz	
Reverse transfer capacitance	Crss	-	9.7	-	pF	V _{GS} =0 V, V _{DS} =40 V, <i>f</i> =1 MHz	

Gate charge characteristics⁴⁾ Table 6

Davamatav	C. mah al		Values			Note / Test Condition
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition
Gate to source charge	Q _{gs}	-	t.b.d.	-	nC	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 5 V
Gate charge at threshold	$Q_{g(th)}$	-	t.b.d.	-	nC	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 5 V
Gate to drain charge ³⁾	$Q_{ m gd}$	-	3.2	-	nC	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 5 V
Switching charge	Q _{sw}	-	t.b.d.	-	nC	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 5 V
Gate charge total ³⁾	Qg	-	11.0	-	nC	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 5 V
Gate plateau voltage	V _{plateau}	-	2.6	-	V	V _{DD} =40 V, I _D =25 A, V _{GS} =0 to 5 V
Output charge ³⁾	Q _{oss}	-	35	-	nC	V _{DD} =40 V, V _{GS} =0 V
	*				•	•

 $^{^{1)}}$ When tested without the specified V_{GS} pre-bias, V_{GS(th)} will typically be 0.7 V lower than the threshold voltage measured under the specified conditions. $^{2)}$ R_{DS(ON)} is measured without prior drain bias or switching stress. An upcoming application note will provide detailed information about dynamic R_{DS(ON)} and recommendations for *in situ* measurement in target application conditions. $^{3)}$ Defined by design. Not subject to production test. $^{4)}$ See "Gate charge waveforms" for parameter definition

⁴ **Target Data Sheet** Rev. 0.1, 2024-05-20

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Table 7 Reverse operation

Paramata	Cy made al	Values			11:4	Nata / Tant Can dition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Reverse continuous current	Is	-	-	t.b.d.	Α	T _C =25 °C	
Pulsed current, reverse	I _{S,pulse}	-	-	t.b.d.	Α	T _C =25 °C	
Source-Drain reverse voltage	V _{SD}	-	2.4	3.4	V	V _{GS} =0 V, I _S ,pulse=25 A, T _j =25 °C	
Reverse recovery charge ¹⁾	Q _{rr}	-	0	-	nC	V_R =40 V, I_S ,pulse=25 A, di_S ,pulse/ dt =100 A/ μ s	



Rev. 0.1, 2024-05-20



4 Electrical characteristics diagrams





5 Package Outlines

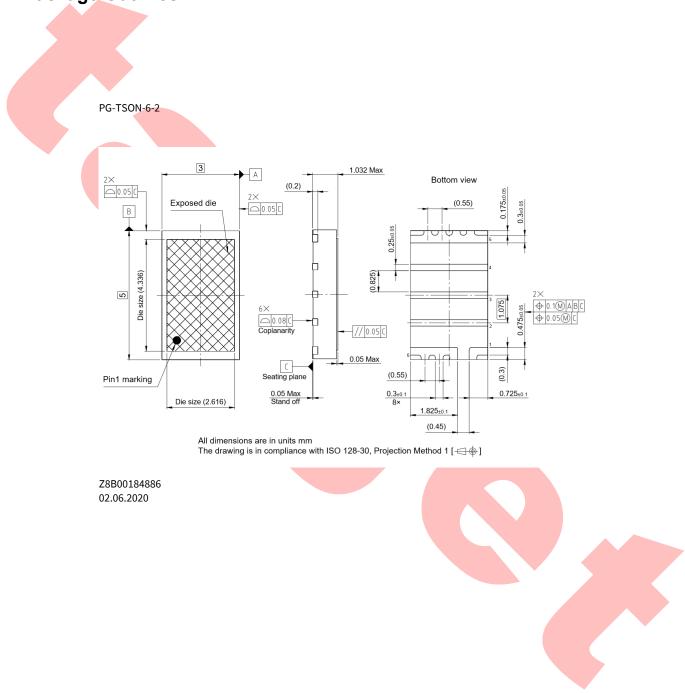


Figure 1 Outline PG-TSON-6, dimensions in mm

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Revision History

IGC025S08S1

Revision: 2024-05-20, Rev. 0.1

Previous Revision

Rev	ision	Date	Subjects (major changes since last revision)
0.1		-	Release of target version

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